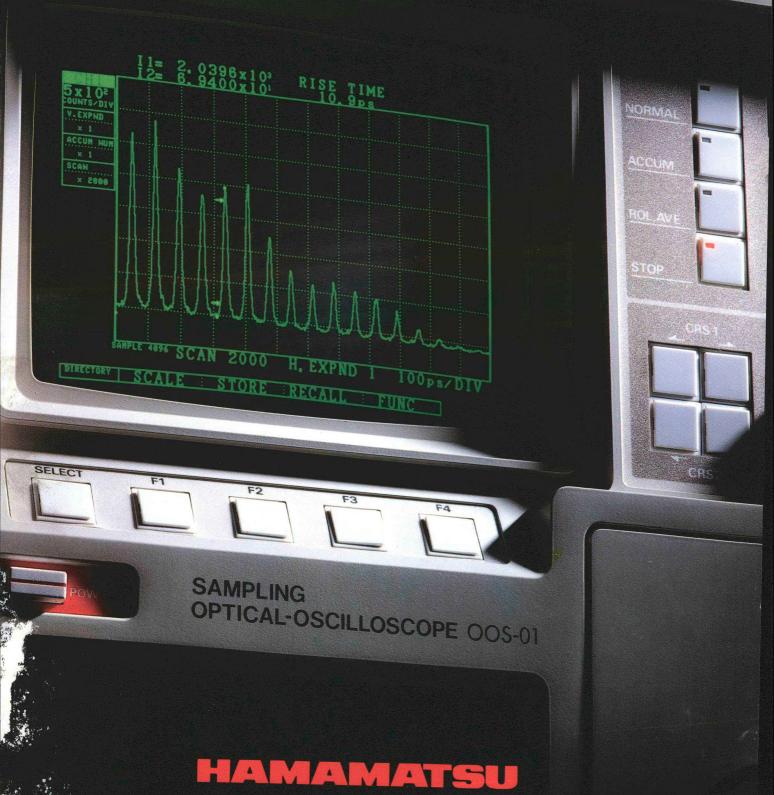
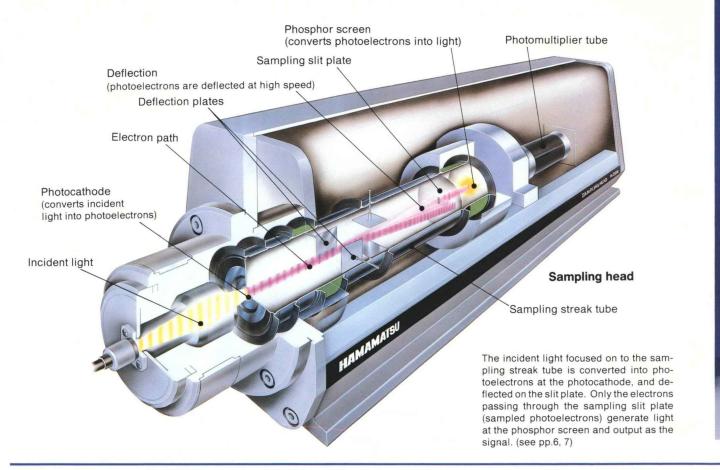
OPTICAL OSCILLOSCOPE 00S-01

New sampling method enables observation of optical waveforms above 30 GHz without distortion





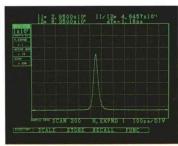
A World's First! Electronic processing with one photoelectron tube from light detection

FEATURES • No distortion

Processing from light detection to electron sampling performed in the sampling streak tube does not generate any waveform distortion such as ringing, reflection, overshoot and sag.



▲ Example of measurement using photodiode and oscilloscope. (100 ps/DIV)



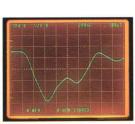
▲ Example of measurement using OOS-01, with none of the ringing observed in the picture on the left. (100 ps/DIV)

Observation of optical waveforms above 30 GHz

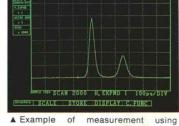
The OOS-01 permits observation of waveforms above 30 GHz — much higher than the 10 GHz which used to be considered the measurement limit for photodetectors and oscilloscopes. (Trigger frequency range is 30 Hz to 1 GHz.)

• 10 ps time resolution

With time resolution better than 10 ps, the OOS-01 has superb response. High speed phenomena which could not be measured before can now be captured accurately.



▲ Example of measurement using photodiode and oscilloscope. (100 ps/DIV)

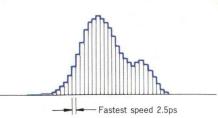


l= 4.0400x10⁴ I1/12= 4.3913x10⁴ 2= 9.2000x10¹ dT= 480.0ps

OOS-01 showing the sharp rising and falling waveforms. (100 ps/DIV)

Waveforms displayed at high resolution

High-precision analysis is performed at the high sampling interval of 2.5 ps. This makes it possible to produce accurate measurement of waveforms involving fine structure which could not previously be observed.



OSCILLOSCOPE REVOLUTION!

A single new photoelectron tube is rewriting the oscilloscope's history..... The OOS-01 sampling optical oscilloscope uses a photoelectron tube — sampling streak tube — developed by Hamamatsu Photonics in a new method of optical measurement.

The sampling streak tube is not only a photodetector. All the processing from light detection to electron sampling is performed in one tube (electronic sampling). The signal transmission line reguired to link a photodetector and a conventional oscilloscope can now be dispensed with, using the new OOS-01. This eliminates the ringing and waveform distortion due to the transmission line, and enables accurate optical intensity waveform measurement. The OOS-01 also realizes time resolution better than 10 ps for the best performance in the world



pling. Permits observation of optical waveforms above 30 GHz without distortion.

Optical measurement has become much easier

The OOS-01 combines photodetector, circuitry, and oscilloscope in one unit. Eliminating the problems in selecting photodetector and oscilloscope equipment, the OOS-01 makes optical measurement much easier.

Data analysis and calculation functions

Accumulation, time axis expansion, waveform calculation (arithmetic operations, FFT), and cursor functions (rise and fall time, FWHM, maximum and minimum values, modulation factor) are among the many easy-to-use functions included as standard features. (See Analysis and Calculation Functions, pp.4, 5.)

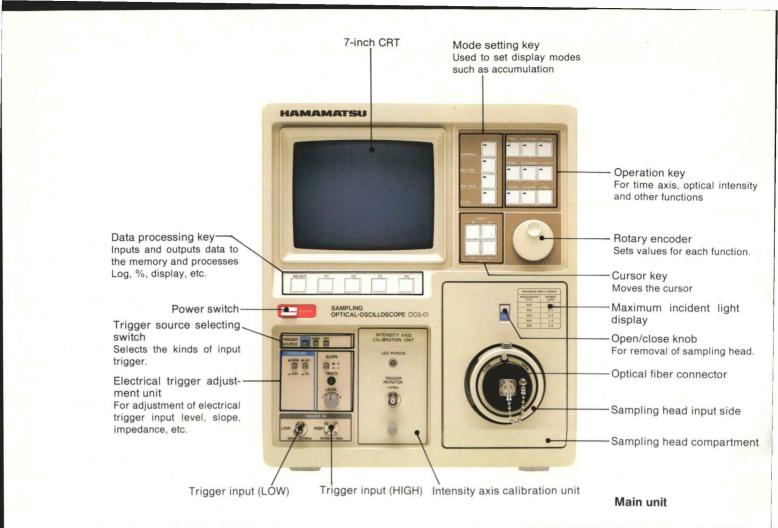
- Enables high-speed sampling at up to 2 MHz
- Measuring wavelength region OOS-01/VIS 350 to 850 nm OOS-01/IR 400 to 1550 nm
- Dynamic range is more than 1:1000
- Four waveforms can be stored in memory
- GPIB interface provided as standard feature

• Two optical signals can be measured at the same time A second sampling head (option) can be attached for dual channel measurement. For example, when measuring the fluorescence life time, both the excitation light and fluorescence can be measured simultaneously.

• Sampling head can be separated from main unit

The sampling head, which consists of a sampling streak tube, a photomultiplier tube and the signal output circuit, can be separated from the main unit. It can therefore be placed on the optical bench — close to where the measurement must be made.





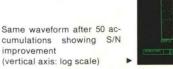
ANALYSIS AND CALCULATION FUNCTIONS

1 Accumulation function

For waveforms that are difficult to see due to noise or fluctuations, this function provides improved S/N ratio by means of waveform accumulation (addition). Up to 10,000 waveforms may be accumulated.



Example of real time measurement (1 accumulation vertical axis: log scale)



2 Time axis expansion function

The time axis can be expanded by factors of 2, 4, and 8 for waveform observation.

3 Waveform calculation functions

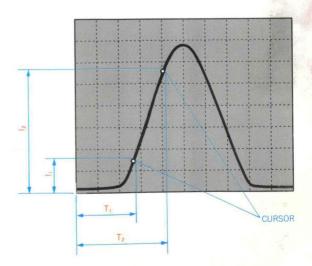
The four arithmetic operations $(+, -, x, \div)$ on two different waveforms and FFT (Fast Fourier Transform) can be performed.

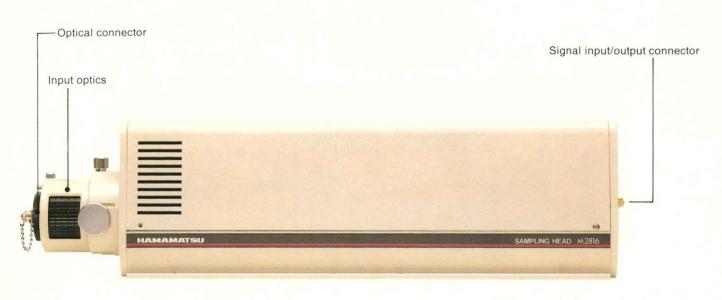
4 Cursor functions

Time and optical intensity display

Time intervals and intensity ratio between the positions specified with two cursors, and intensities specified at cursors can also be displayed.

Measurement parameters : Time T1 – T2 : Intensity I1, I2, I1/I2



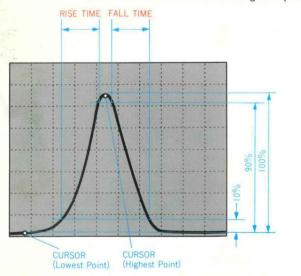


Sampling head (Can be used installed in the main unit or separated from the main unit)

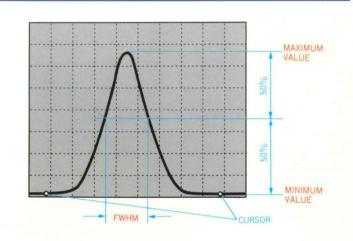
Rise time, fall time measurement

The rise and fall times of optical phenomena can be measured and displayed by setting the cursors to the highest and lowest points of the waveform.

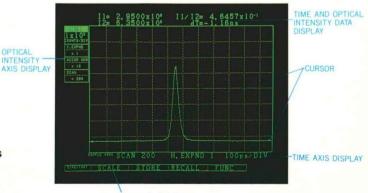
Rise time : This is the time required for the signal to rise from 10% to 90% of the highest point.Fall time : This is the time required for the signal to fall from 90% to 10% of the highest point.



• Measurement of FWHM, Minimum Value, Maximum Value, Modulation Factor, and Area Between Cursors By setting the cursors to points before and after the waveform, the FWHM, minimum value, maximum value modulation factor and area between cursors are measured and displayed.



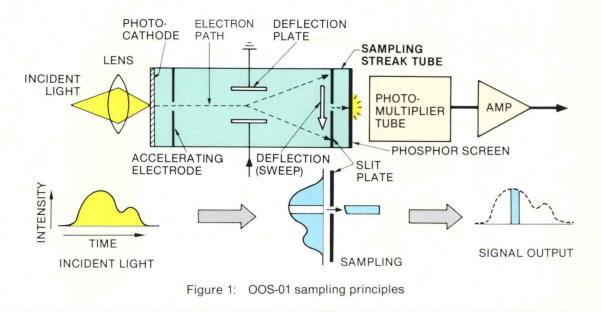




FUNCTION DISPLAY

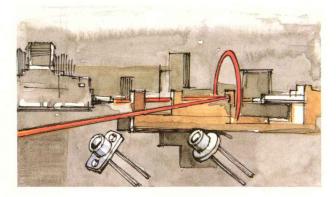
OPERATING PRINCIPLES

The sampling streak tube — a single photoelectron tube which performs all the functions from light detection through sampling — is the heart of the OOS-01. This unique tube (see Figure 1) converts the light incident on the photocathode into photoelectrons in proportion to the input

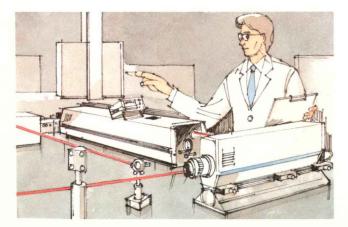


APPLICATION EXAMPLES

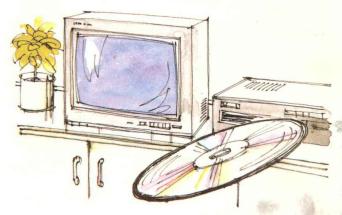
 Evaluation and inspection of response characteristics for visible and infrared semiconductor lasers and ultra high-speed light source



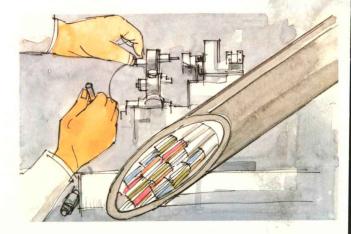
• Evaluation and inspection of mode-locked laser systems such as argon ion laser or Nd-Yag-laser.



 Evaluation and inspection of optical components used in optical discs (CD, video disc)

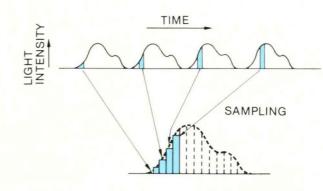


 Evaluation and inspection of transmission characteristics of optical fiber.



light intensity. These photoelectrons are accelerated and directed by the accelerating electrode past a pair of deflection electrodes towards the sampling slit plate. As they pass the deflection electrodes, they are deflected at high speed past a narrow slit on the sampling slit plate. Only the electrons which pass through the sampling slit are

directed to the phosphor screen, where they are converted to light which is detected and converted into an electrical signal by a photomultiplier tube. This electronically sampled signal is then stored and processed. The sampling operation can be repeated many times with different delay timing between the trigger and the sampling to produce a waveform of optical intensity versus time of the incident light. (See Figure 2.)

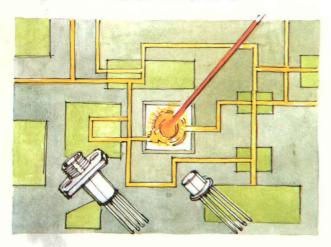




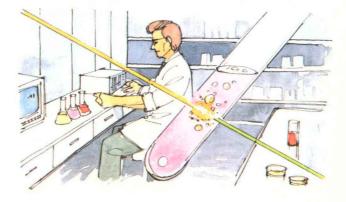
 Evaluation of characteristics of optical transmission systems in optical LAN and other equipment



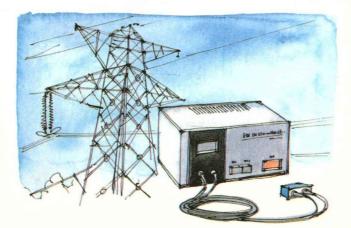
Evaluation of characteristics of optical ICs



 Spectrophotometry, fluorescence lifetime measurement in picosecond to microsecond range



 Measurement of physical quantities when combined with E/O converters and fiber sensors



SPECIFICATIONS

Sampling Head (M2816, M2816-01)

Optical signal input form	Fixed slit &
	optical connector
Spectral response (sensitive wavelength range)	
M2816 for OOS-01/VIS	350 to 850 nm
M2816-01 for OOS-01/IR	400 to 1550 nm
Effective detection area	2.5(H) x 0.03(W) mm
	(when fixed slit is used)
Time resolution	Better than 10 ps
	(equivalent to $fc > 30 GHz$)
Setting position	Installed in the main unit
or	separated from the main unit

Main Unit

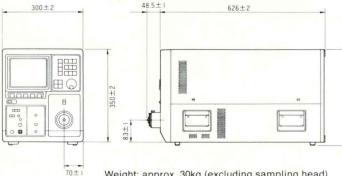
Time axis 20 ps/div. to 1 µs/div.	
Number of sampling points 4096, 2048, 1024, 512, 256	
points/full scale	
Scan rate 1 to 10,000 events/dot	
Sampling rate 2 MHz maximum	
Sampling interval 2.5 ps minimum	
Jitter Less than 20 ps	
Rise and fall times (incl. jitter) Less than 20 ps	
Dynamic range More than 1 : 1000	
Trigger repetition rate : LOW 30 Hz to 200 MHz	
(with slew rate more than 0.75 V/ μ s)	
: HIGH 150 MHz to 1 GHz	
A/D converter	
Number of waveform memory 4	
(Capacity : 4096 x 32 bits)	
Accumulation function 1 to 10,000 times	
Time-axis expansion function 2, 4, 8 times	
Waveform calculation function	
Arithmetic operations $(+, -, x, \div)$ on two different	

Arithmetic operations $(+, -, x, \div)$ on two different waveforms, FFT (Fast Fourier Transform) Cursor function

Rise time, fall time, FWHM, minimum value, maximum value, modulation factor, intensities specified at cursors, intensity ratio, area between cursors, time interval between the positions of two specified cursors.

Intensity axis display function W, linear, %, Log, Ln

Main Unit



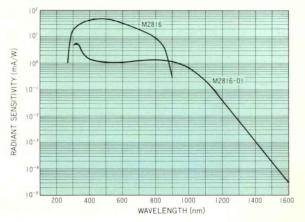
Options

Optical trigger head: M2970 Optical connector adaptor: (FC) A2971-00 (D4) A2971-01 (OF2) A2971-02 (Bi-conic) A2971-03 (SMA) A2971-04 (ST) A2971-05 One of the above optical connector adaptors is available as standard. Polaroid camera: A3196 Transfer cart

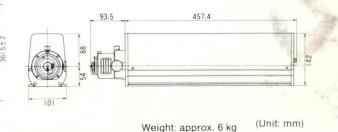
General and Environmental Specifications

Line voltage 100/117 or 220/240 VAC, 50/60 Hz
Power consumption Approx. 250 VA
Operating temperature 0 to +40°C
Storage temperature 10 to + 50°C
Operating and storage humidity Below 70%
(no condensation)

Spectral response



Sampling Head



CR-5000 Printed in

Weight: approx. 30kg (excluding sampling head)

Specifications and external appearance are subject to change without notice.

HAMAMATSU

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